

600V Super-Junction Power MOSFET

DESCRIPTION

600V Super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle and pioneered. The Multi-EPI SJ MOSFET provide an extremely fast and robust body diode. Also provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

FEATURES	APPLICATIONS
Ultra-fast body diode	• Switch Mode Power Supply (SMPS)
● Very low FOM R _{DS(on)} ×Q _g	 Uninterruptible Power Supply (UPS)
• Easy to use/drive	 Power Factor Correction (PFC)
 100% avalanche tested 	LLC Half-bridge
 RoHS compliant 	• Charger
Gate G D S	Drain CROHS Source

Device Marking and Package Information				
Device	Package	Marking		
TPA60R260MFD	TO-220F 60R260MFD			
Key Performance Parameters	S			
Parameter	Value	Unit		
V _{DS} @ T _{j,max}	600	V		
R _{DS(on),max}	0.26	Ω		
I _D	15	А		
Q _{g,typ}	28.5	nC		
I _{DM}	45	А		
t _{rr}	137	ns		
Q _{rr}	0.73	μC		
I _{rrm}	10.6	A		



Absolute Maximum Ratings $T_c = 25^{\circ}C$, unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	600	V
Continuous Drain Current	T _C = 25°C		15	А
Continuous Drain Current	TC = 100°C	I _D	9	
Pulsed Drain Current	(note1)	I _{DM}	45	А
Gate-Source Voltage		V _{GSS}	±30	V
Single Pulse Avalanche Energy	(note2)	E _{AS}	284	mJ
Repetitive Avalanche Energy (note2)		E _{AR}	0.44	mJ
Avalanche Current		I _{AR}	2.4	А
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50	V/ns
Power Dissipation		P _D	32	W
Continuous Body Diode Current		۱ _s	15	
Pulsed Diode Forward Current (note1)		I _{SM}	45	A
Reverse diode dv/dt (note3)		dv/dt	15	V/ns
Maximum diode commutation speed (note3)		di _f /dt	500	A/us
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150	°C

Thermal Resistance				
Parameter Symbol Value				
Thermal Resistance, Junction-to-Case	R _{thJC}	3.9	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	80	-C/W	



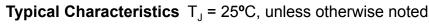
Devenueter		Test Oscillation	Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0V, I _D = 250µA	600			V	
Zoro Cato Voltago Drain Curront		V_{DS} = 600V, V_{GS} = 0V, T_{J} = 25°C			1.75	۵	
Zero Gate Voltage Drain Current	I _{DSS}	V_{DS} = 600V, V_{GS} = 0V, T_{J} = 150°C			1750	μA	
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	3		5	V	
Drain-Source On-Resistance	R _{DS(on)}	V _{GS} = 10V I _D = 7.5A		0.23	0.26	Ω	
Gate resistance	R _G	f = 1.0MHz open drain		12.5		Ω	
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0V,		1194		pF	
Output Capacitance	C _{oss}	V _{DS} = 100V		62			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		2.4			
Total Gate Charge	Qg	V _{DD} = 480V ,		28.5		nC	
Gate-Source Charge	Q_{gs}	I _D = 15A,		8			
Gate-Drain Charge	Q_gd	V _{GS} = 10V		11			
Turn-on Delay Time	t _{d(on)}			27			
Turn-on Rise Time	t _r	$V_{DD} = 400V,$		29			
Turn-off Delay Time	t _{d(off)}	I _D = 15A, R _G = 25Ω		114		ns	
Turn-off Fall Time	t _f			33			
Drain-Source Body Diode Characte	eristics						
Body Diode Voltage	V _{SD}	$T_{\rm J}$ = 25°C, I _{SD} = 7.5A, V _{GS} = 0V		1.0	1.5	V	
Reverse Recovery Time	t _{rr})/ - 400)/		137		ns	
Reverse Recovery Charge	Q _{rr}	$V_{R} = 400V,$ $I_{F} = I_{S},$		0.73		μC	
Peak Reverse Recovery Current	I _{rrm}	di _F /dt = 100A/µs(()		10.6		А	

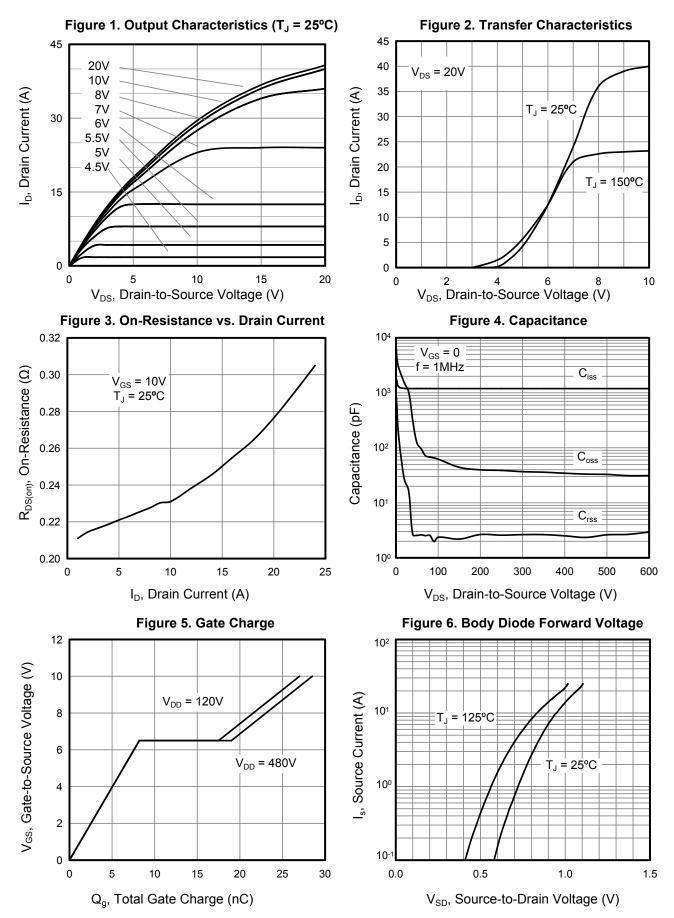
Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_D = 2.4A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
- 3. Identical low side and high side switch with identical ${\rm R}_{\rm G}$

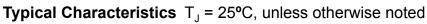


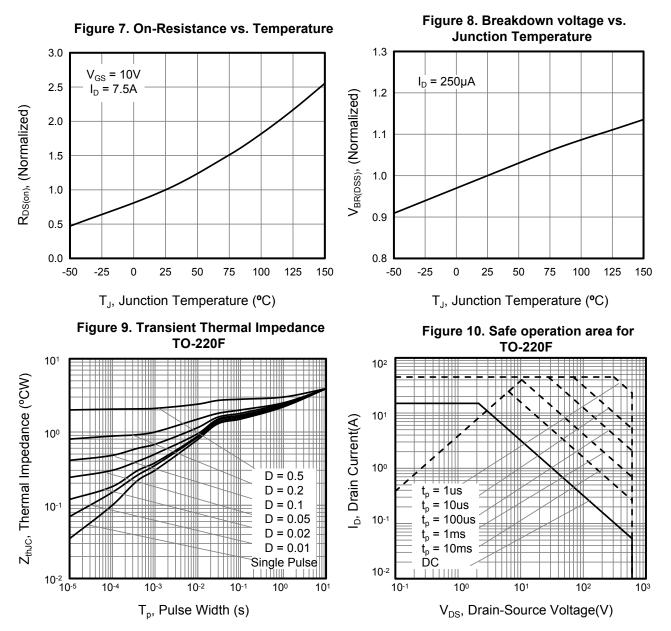
E













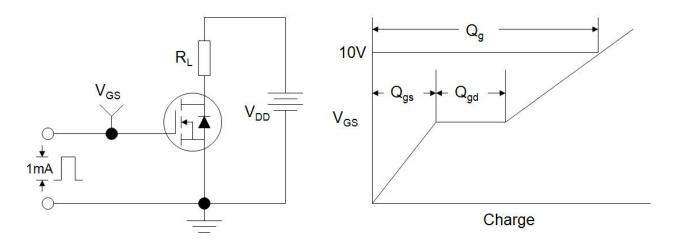


Figure B: Resistive Switching Test Circuit and Waveform

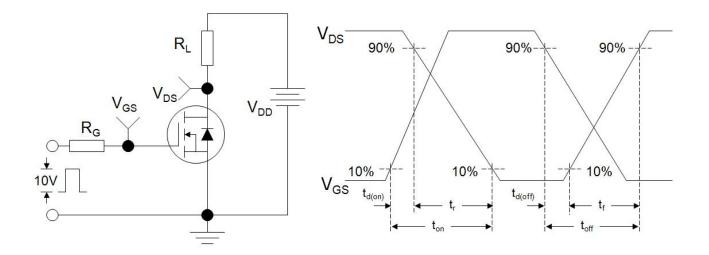
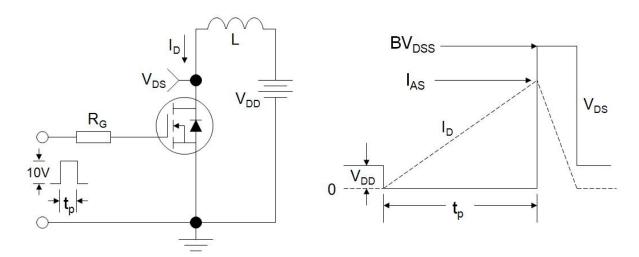
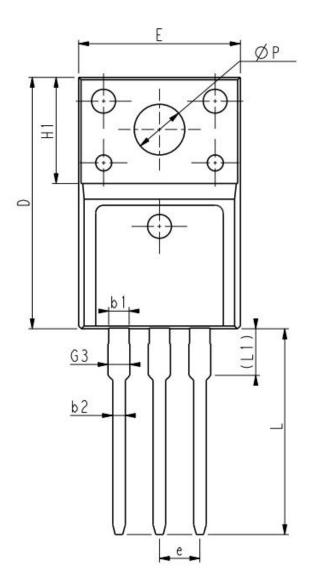


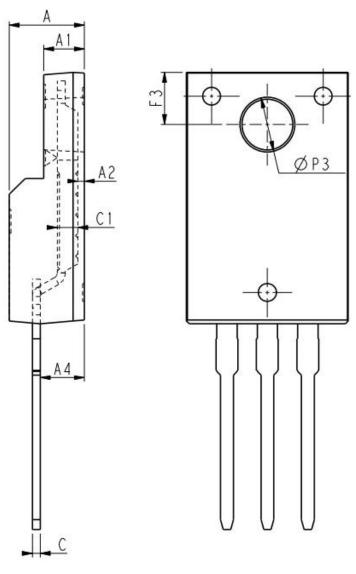
Figure C: Unclamped Inductive Switching Test Circuit and Waveform











	Unit				
Symbol	Min.	Nom	Max.	Symbol	Mir
E	9.96	10.16	10.36	е	
А	4.50	4.70	4.90	L	12.6
A1	2.34	2.54	2.74	L1	2.9
A2	0.30	0.45	0.60	ΦΡ	3.0
A4	2.56	2.76	2.96	ΦΡ3	3.1
с	0.40	0.50	0.65	F3	3.1
c1	1.20	1.30	1.35	G3	1.2
D	15.57	15.87	16.17	b1	1.1
H1	6.70REF			b2	0.7

Unit:mm				
Symbol	Min.	Max.		
е		2.54BSC		
L	12.68	12.98	13.28	
L1	2.93	3.03	3.13	
ΦP	3.03	3.18	3.38	
ΦΡ3	3.15	3.45	3.65	
F3	3.15	3.30	3.45	
G3	1.25	1.35	1.55	
b1	1.18	1.28	1.43	
b2	0.70	0.80	0.95	



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